



SIMONS
ELECTRON
MICROSCOPY
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NYSBC 

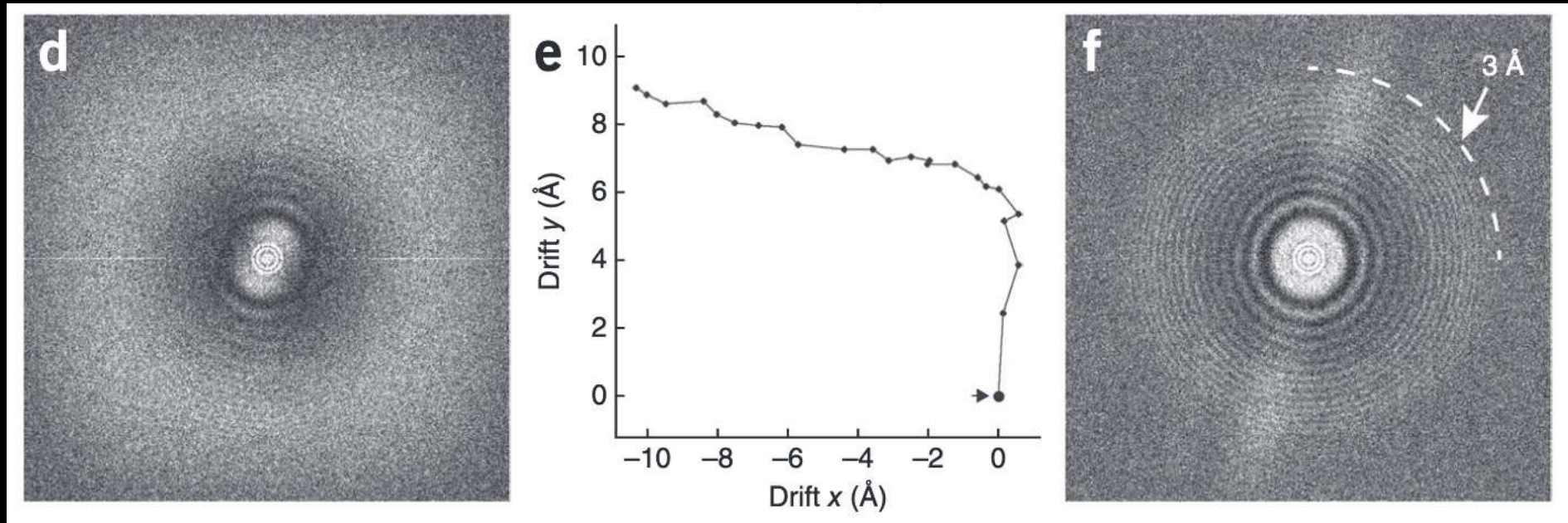
Winter 2023 EM Course

Single-particle workflow

Amedee des Georges

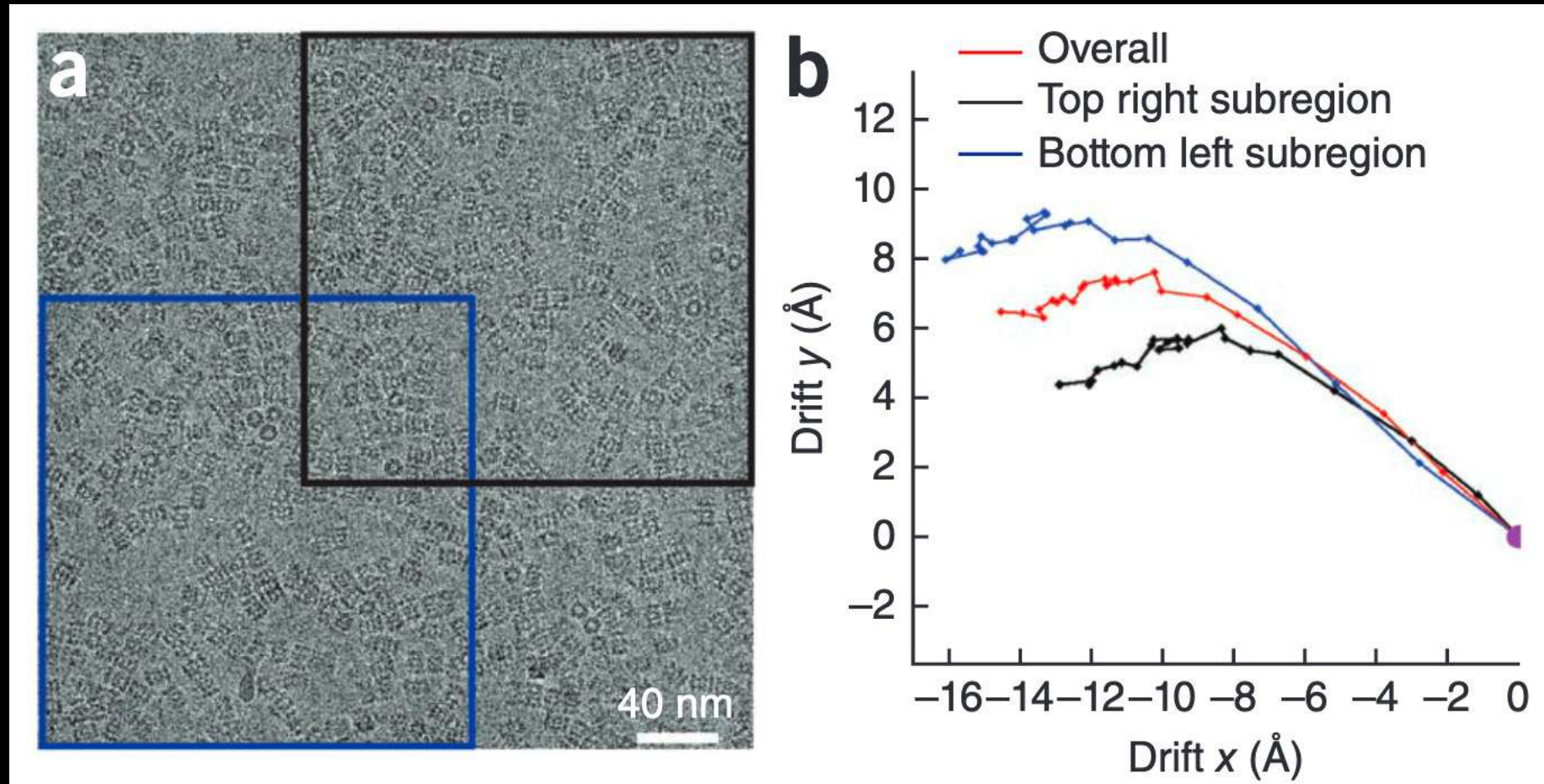
Movie alignment

- Alignment of all frames to their average



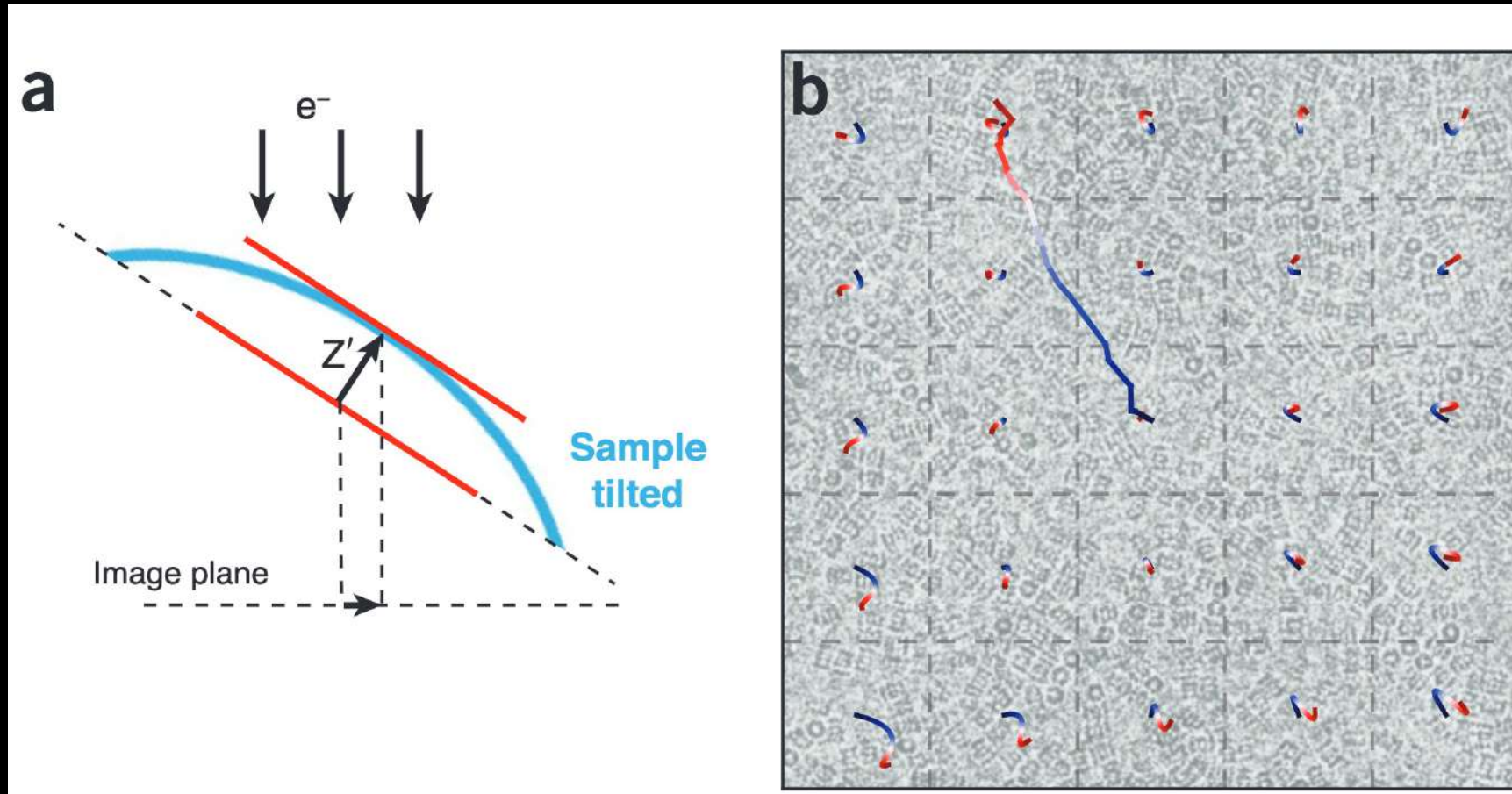
Movie alignment

- Sub-frame alignment



Movie alignment

- Sub-frame alignment



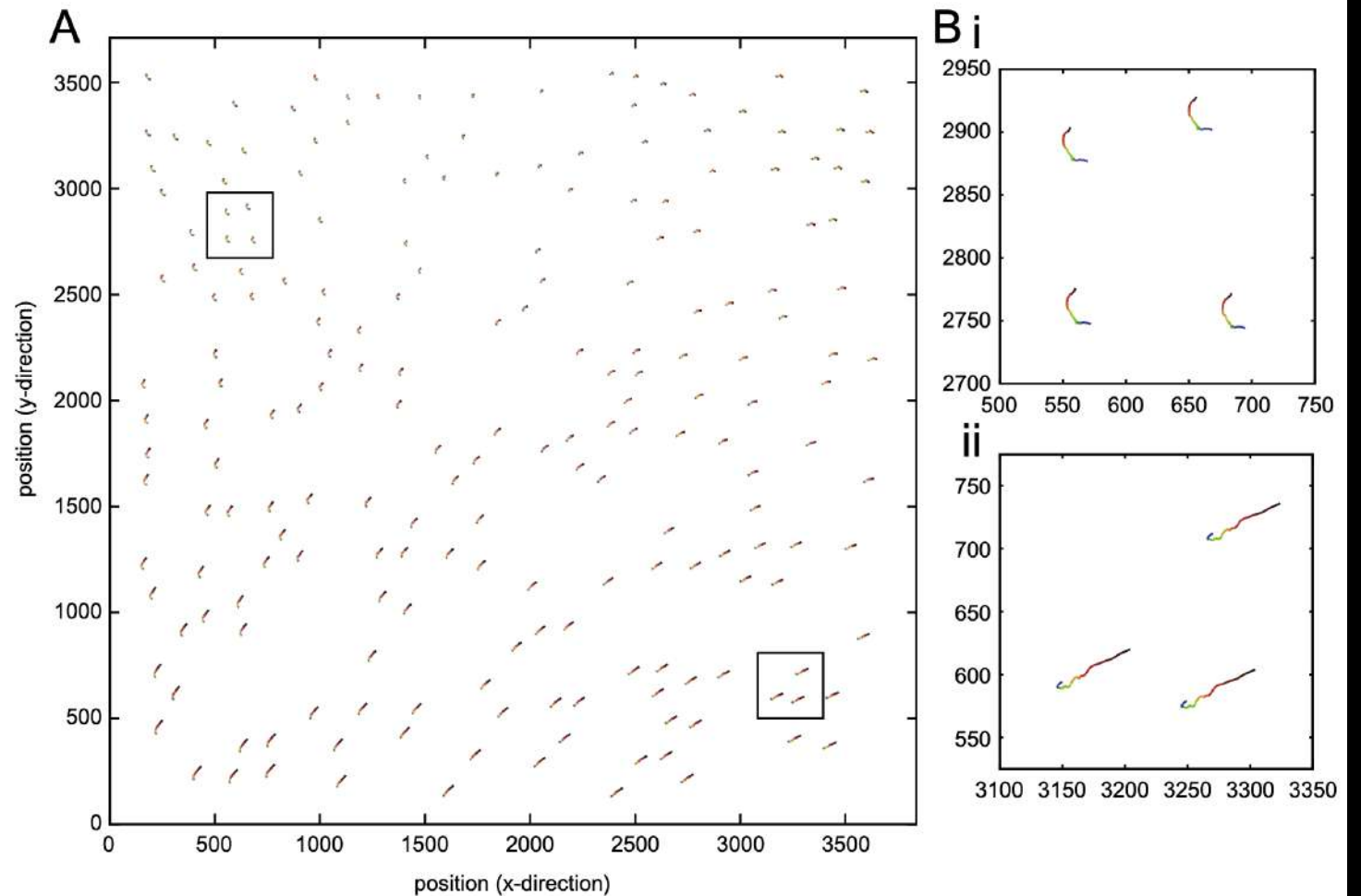
Movie alignment

- Per-particle alignment
 - Relion “polishing”
 - alignment to a reference
 - estimation of contrast loss per frame
 - alignparts_lmbfgs (Rubinstein/cryoSPARC):
 - alignment to self.
 - No re-estimation of contrast loss per frame.

Movie alignment

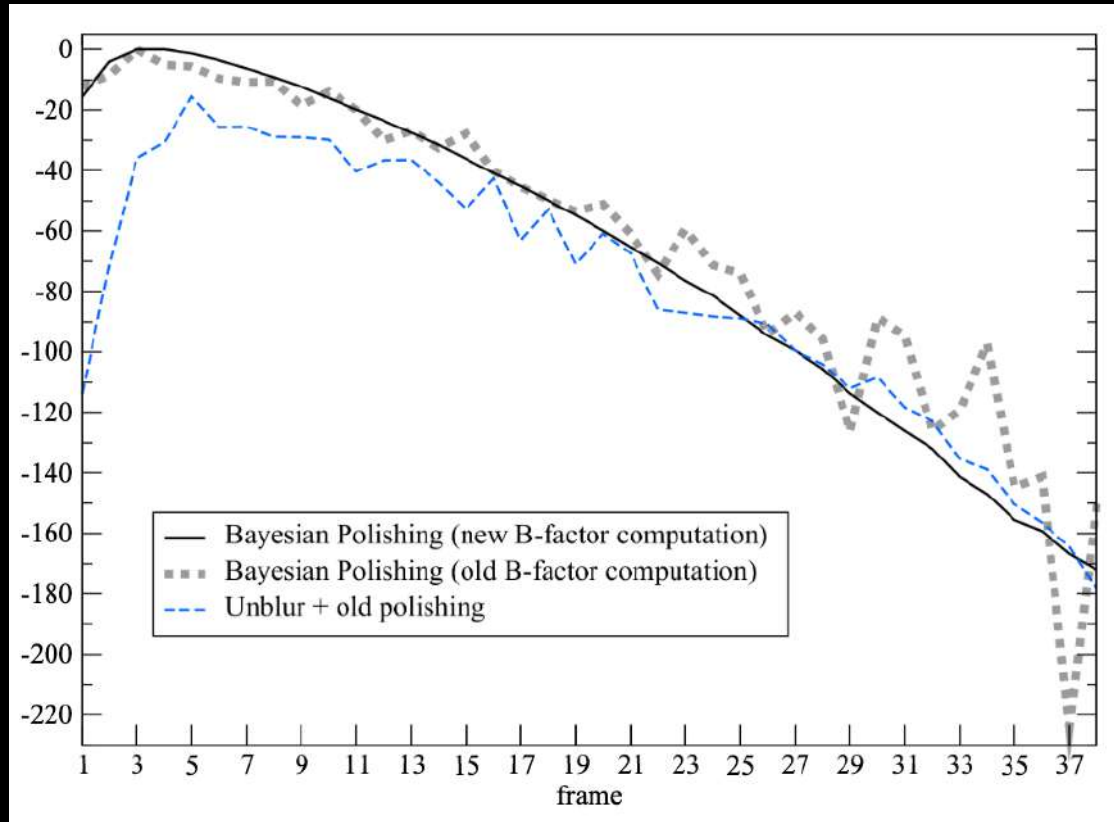
- Per-particle alignment.

J.L. Rubinstein, M.A. Brubaker / Journal of Structural Biology 192 (2015) 188–195



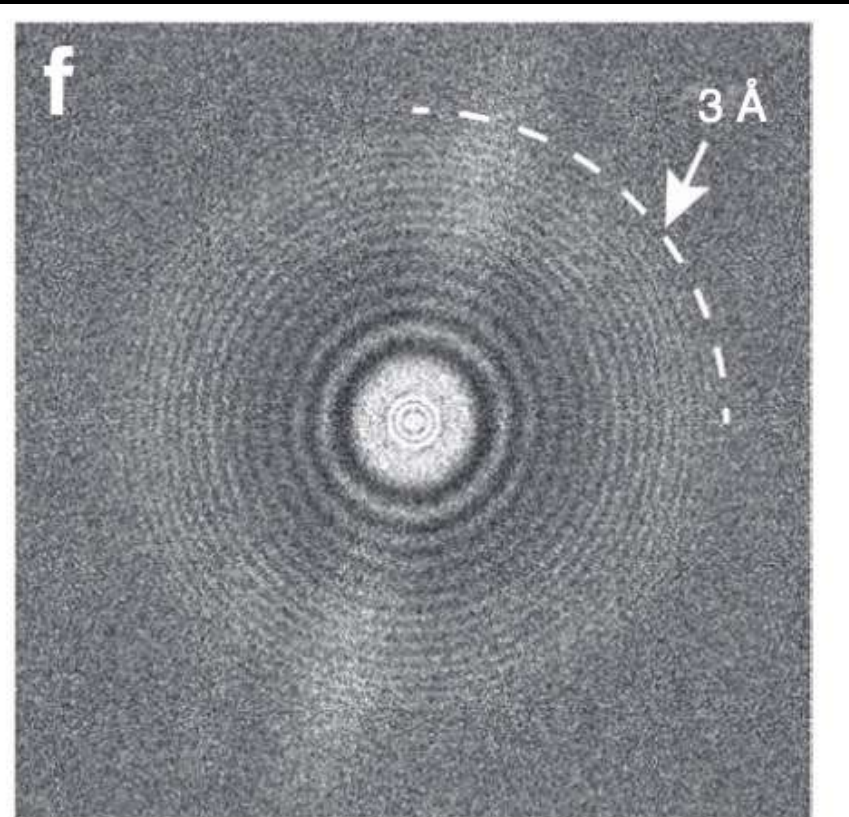
Movie alignment

- Contrast loss and radiation damage correction



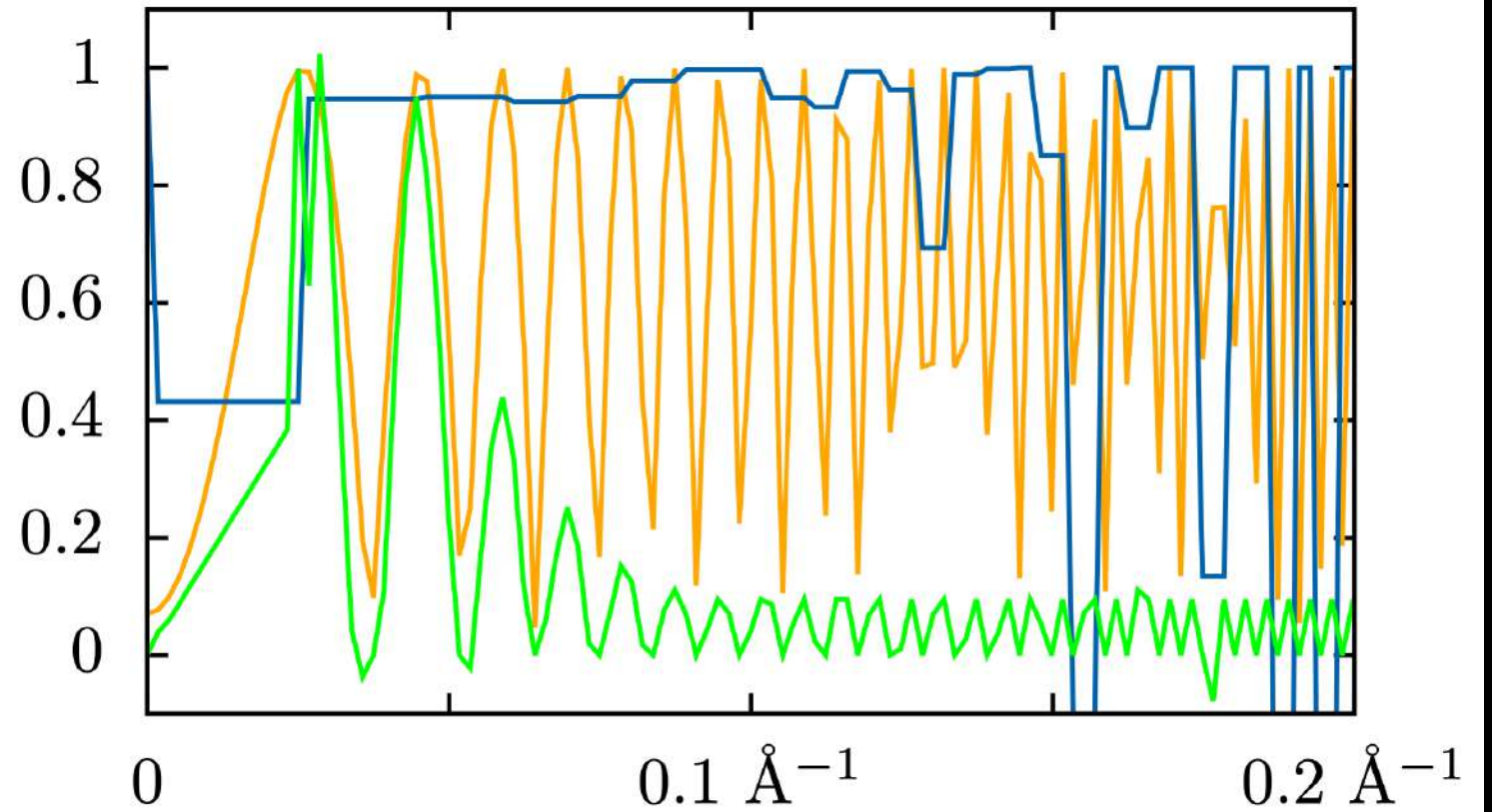
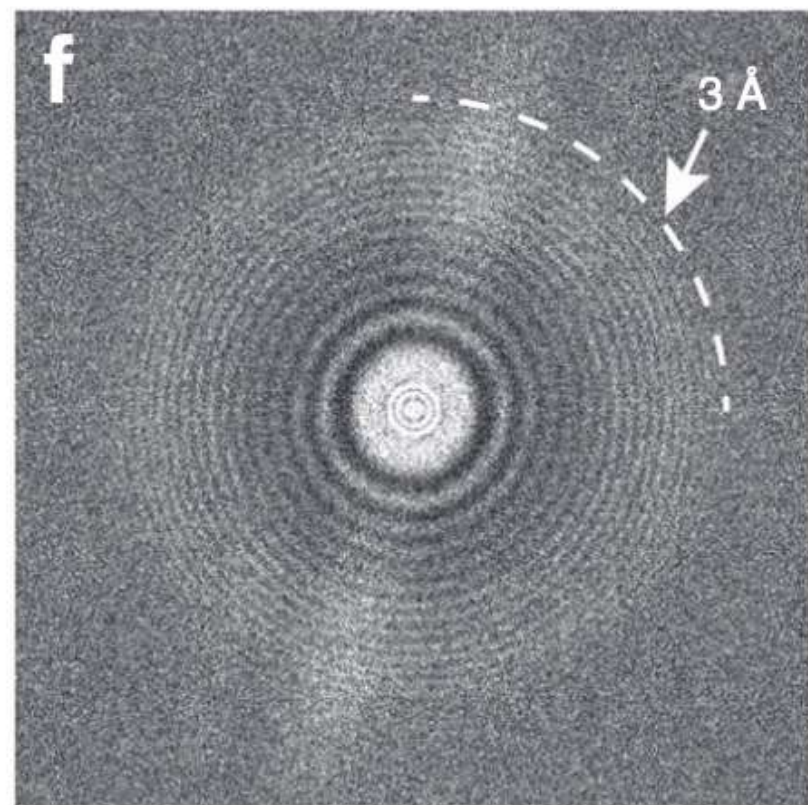
CTF estimation

- Contrast transfer function correction
 - Estimating the defocus value of a micrograph



CTF estimation

- Contrast transfer function correction
 - Estimating the defocus value of a micrograph



CTF estimation

- Contrast transfer function correction
 - Critical for resolution!

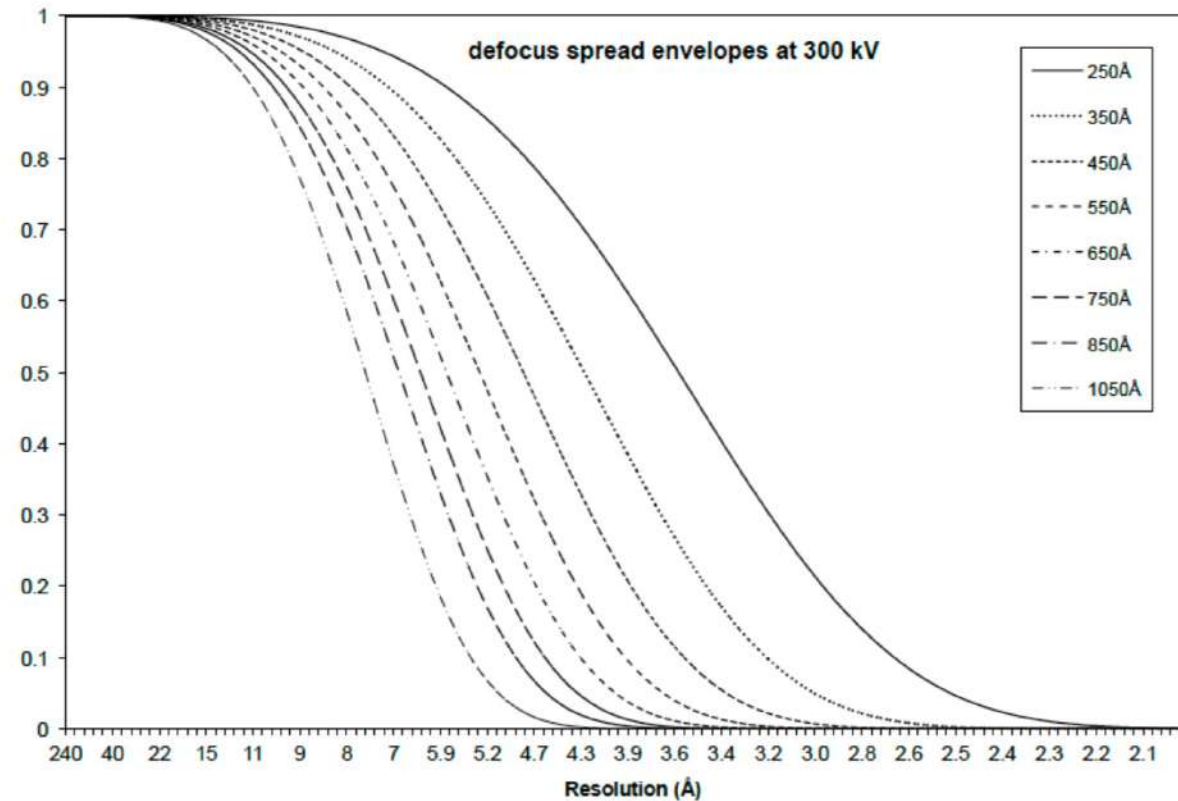
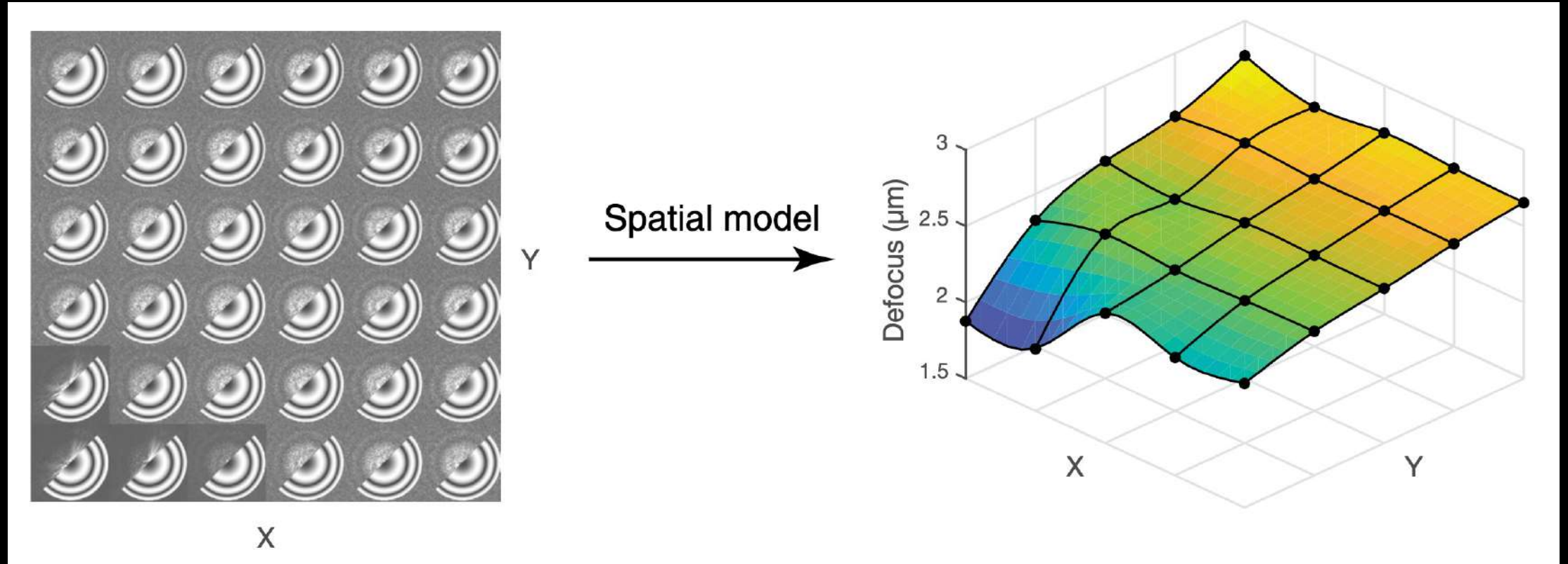


Fig. 5 Defocus spread envelope functions at 300kV. Envelope functions calculated according to Frank (1973) and Wade and Frank (1977) with the SPIDER command TF D.

CTF estimation

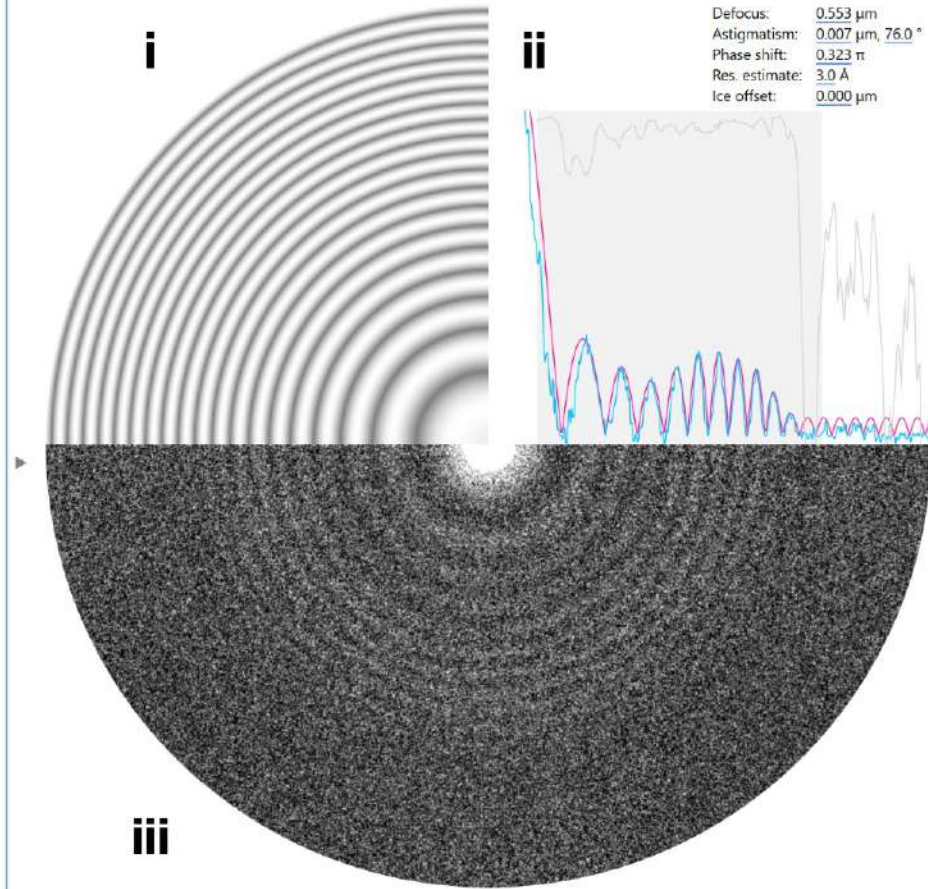
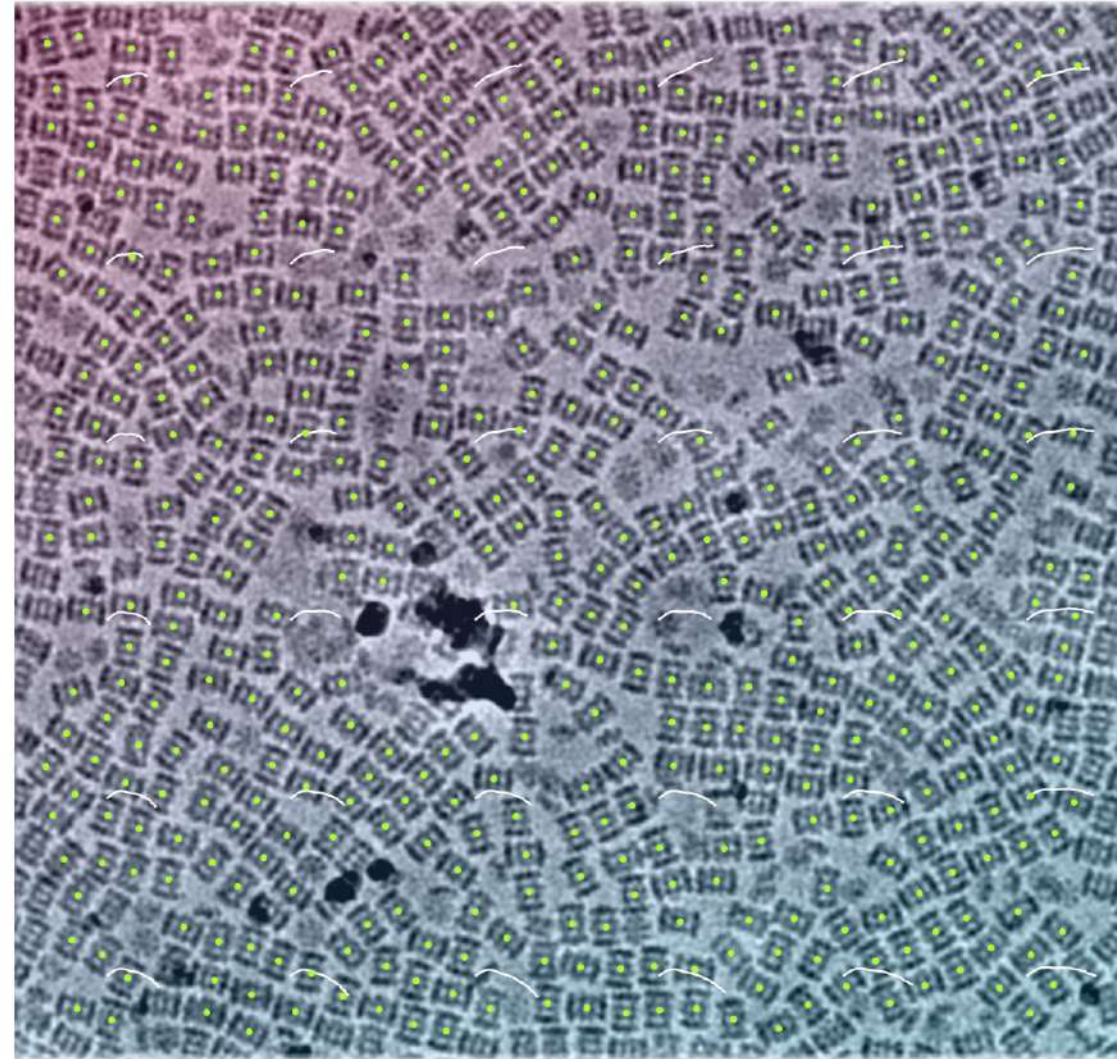
- Contrast transfer function correction
 - Estimating defocus per particle



Raw Data

Overview Fourier & Real Space

PROCESS ONLY THIS ITEM'S CTF

Zoom: 0.25 x Intensity range: 2.50 σ ☒ Deconvolve, strength = 1.00, falloff = 1.00, high-pass = 100 Å☒ Show motion tracks, 20 x scale, 6 x 6 grid, ☐ only local motion ☒ Show elevation, 0.546 μm — 0.558 μm ☒ Show particles from [BoxNet 20180122](#), with 100 Å diameter, at least 0.958 score, ☒ Dots, ☐ flash — 501 particles [APPLY THIS THRESHOLD TO ALL MICROGRAPHS](#)[PICK WITH BOXNET20180122](#) ☐ Show mask, [PAINT](#) with a 300 Å brush

Processed 24/29.

CTF estimation

- Contrast transfer function correction
 - Correction of higher order aberrations
 - At the stage of 3D refinement.

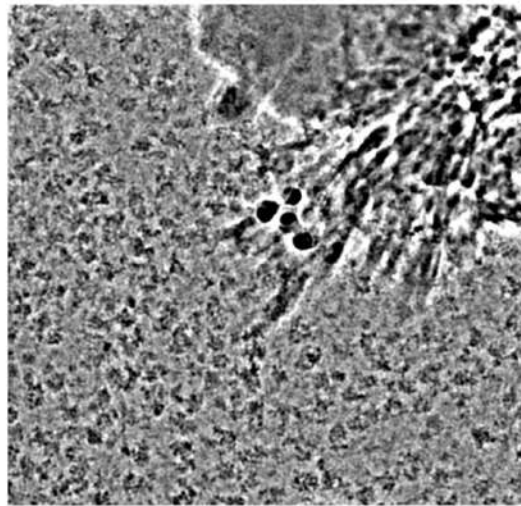
Particle picking

- Deep learning algorithms win over all.

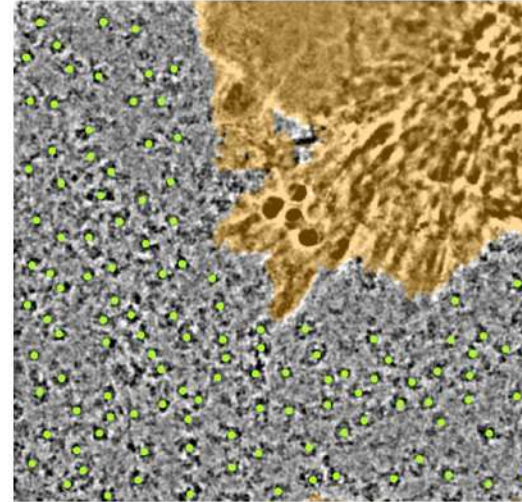
Particle picking

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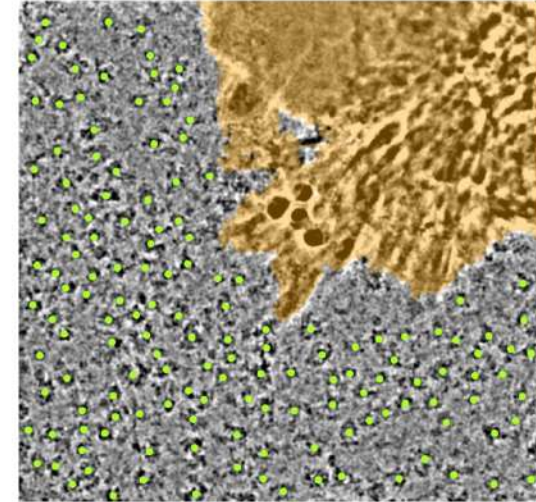
Original image



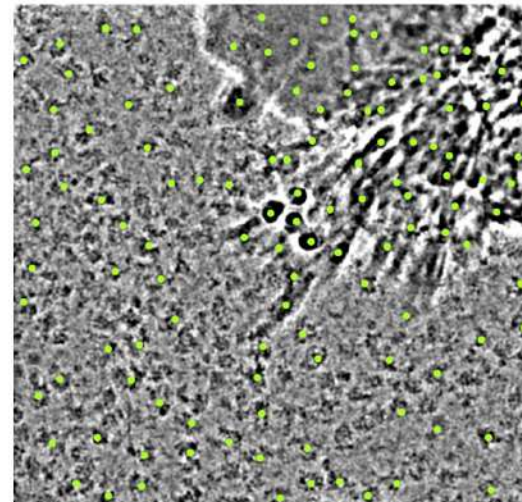
BoxNet, generic



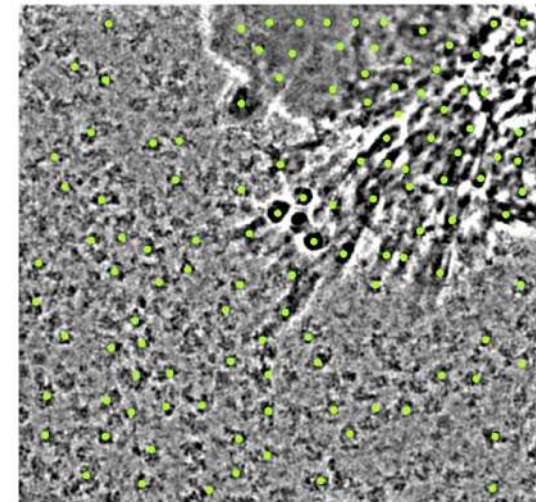
BoxNet, re-trained



RELION, Gaussian blob



RELION, 2D class templates

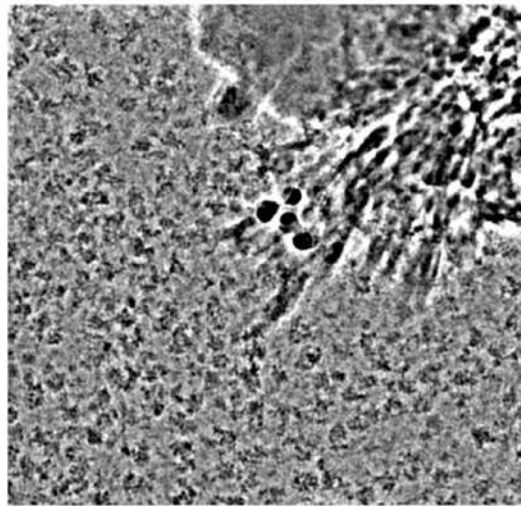


Particle picking

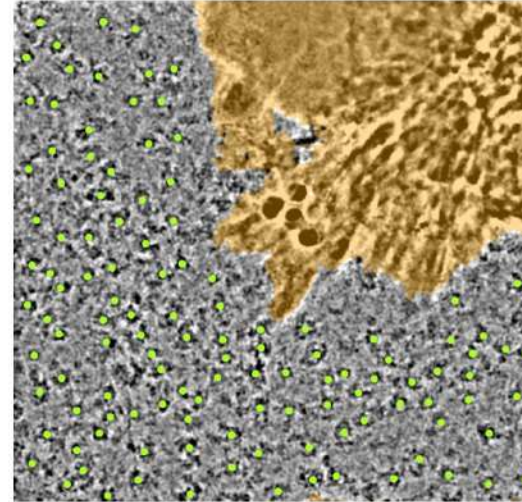
- Deep learning algorithms win over all.

- ✓Warp
- ✓crYOLO
- ✓Topaz

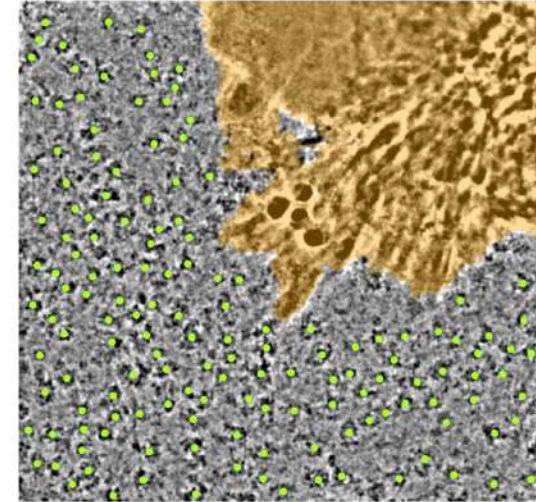
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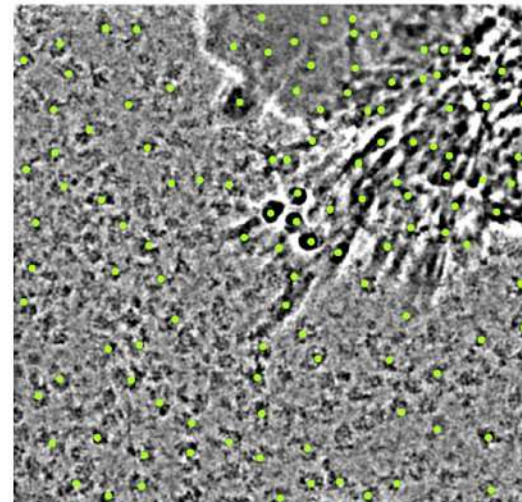
BoxNet, generic



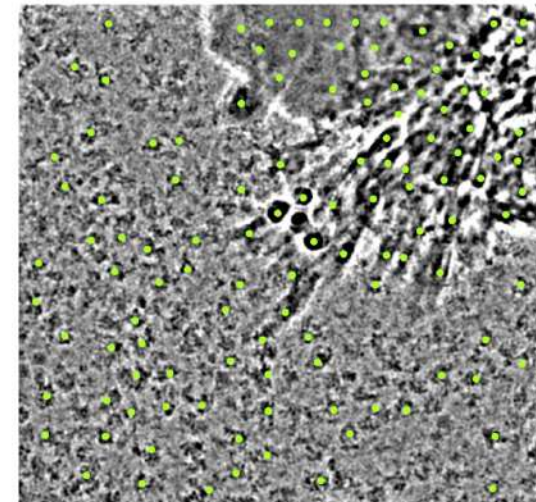
BoxNet, re-trained



RELION, Gaussian blob



RELION, 2D class templates



Initial cleaning of particles

- Many ways of doing it
 - Sorting based on statistics
 - 2D classification
 - Multi-reference ab-initio
 - 3D classification

Initial cleaning of particles

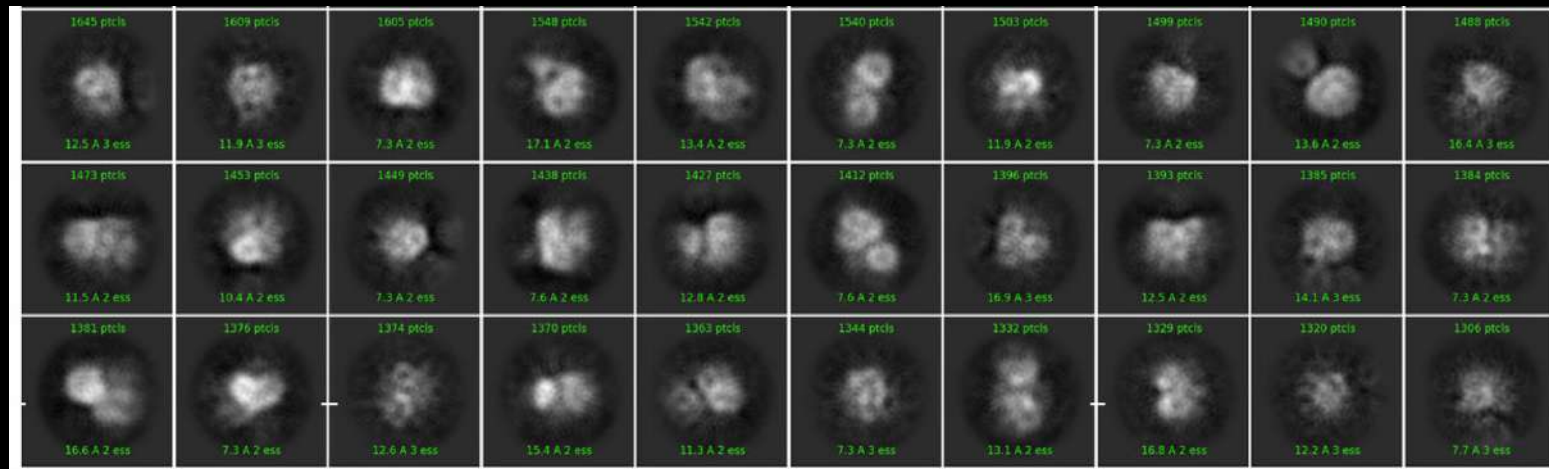
- Many ways of doing it

➤ Sorting based on statistics

➤ 2D classification

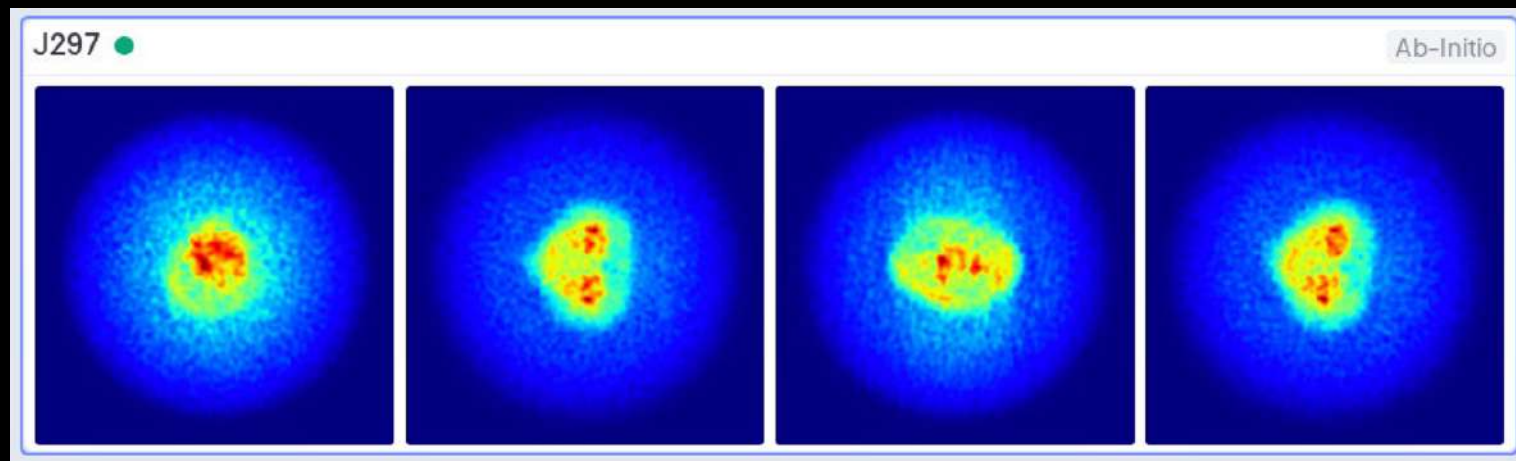
➤ Multi-reference ab-initio

➤ 3D classification



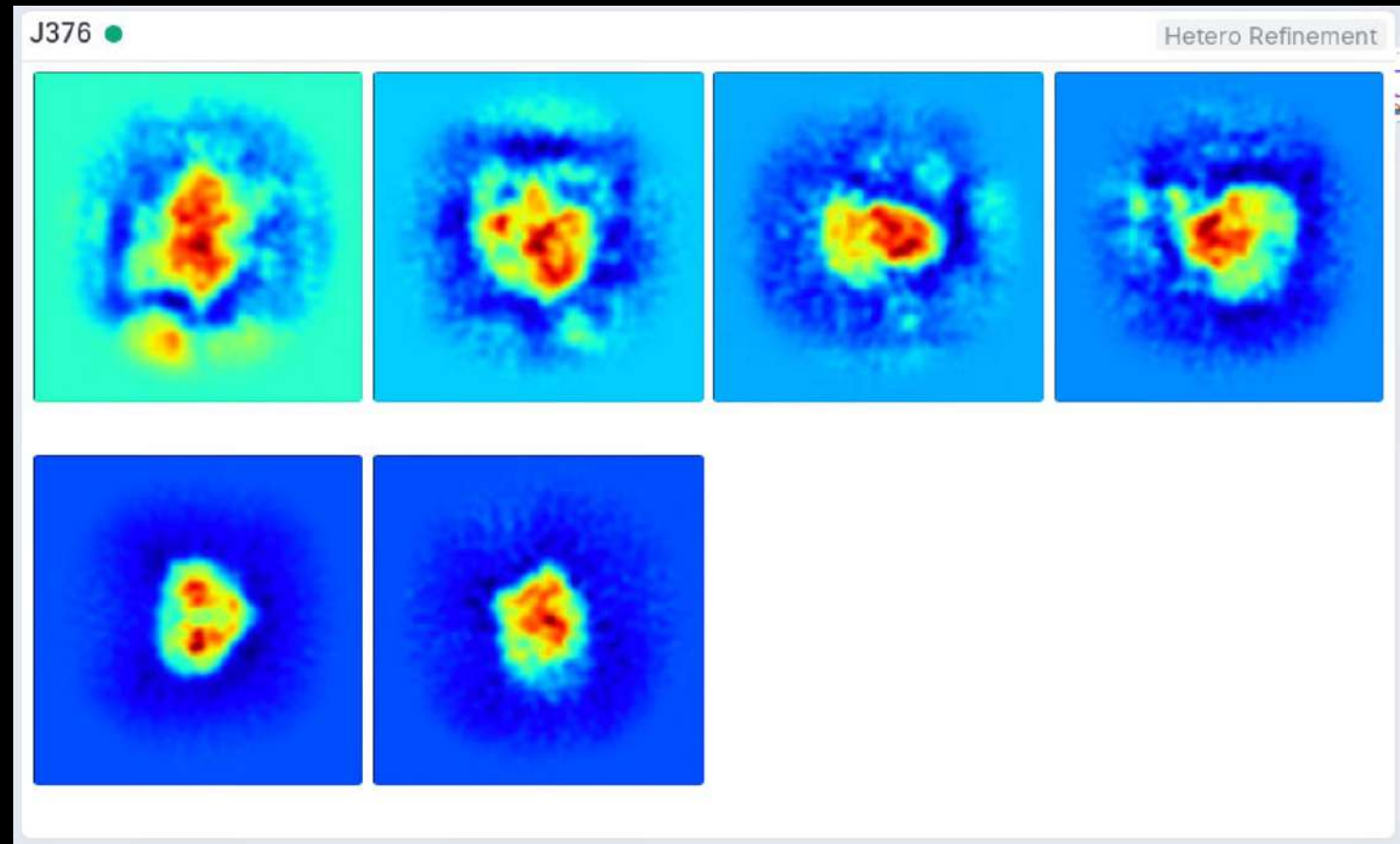
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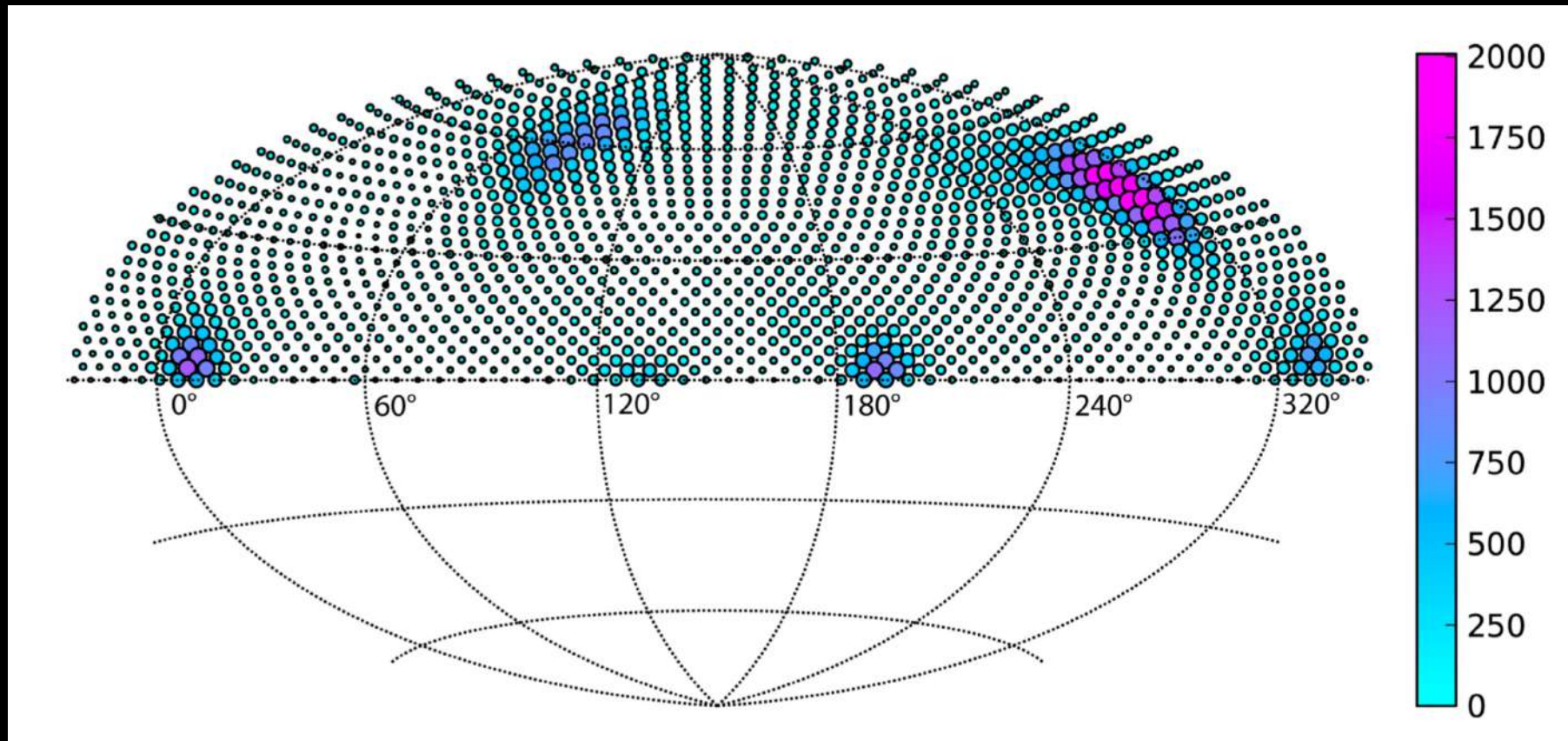
Initial cleaning of particles

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Aligning particles in 3D

- Precision and accuracy -> critical for resolution AND classification.



Aligning particles in 3D

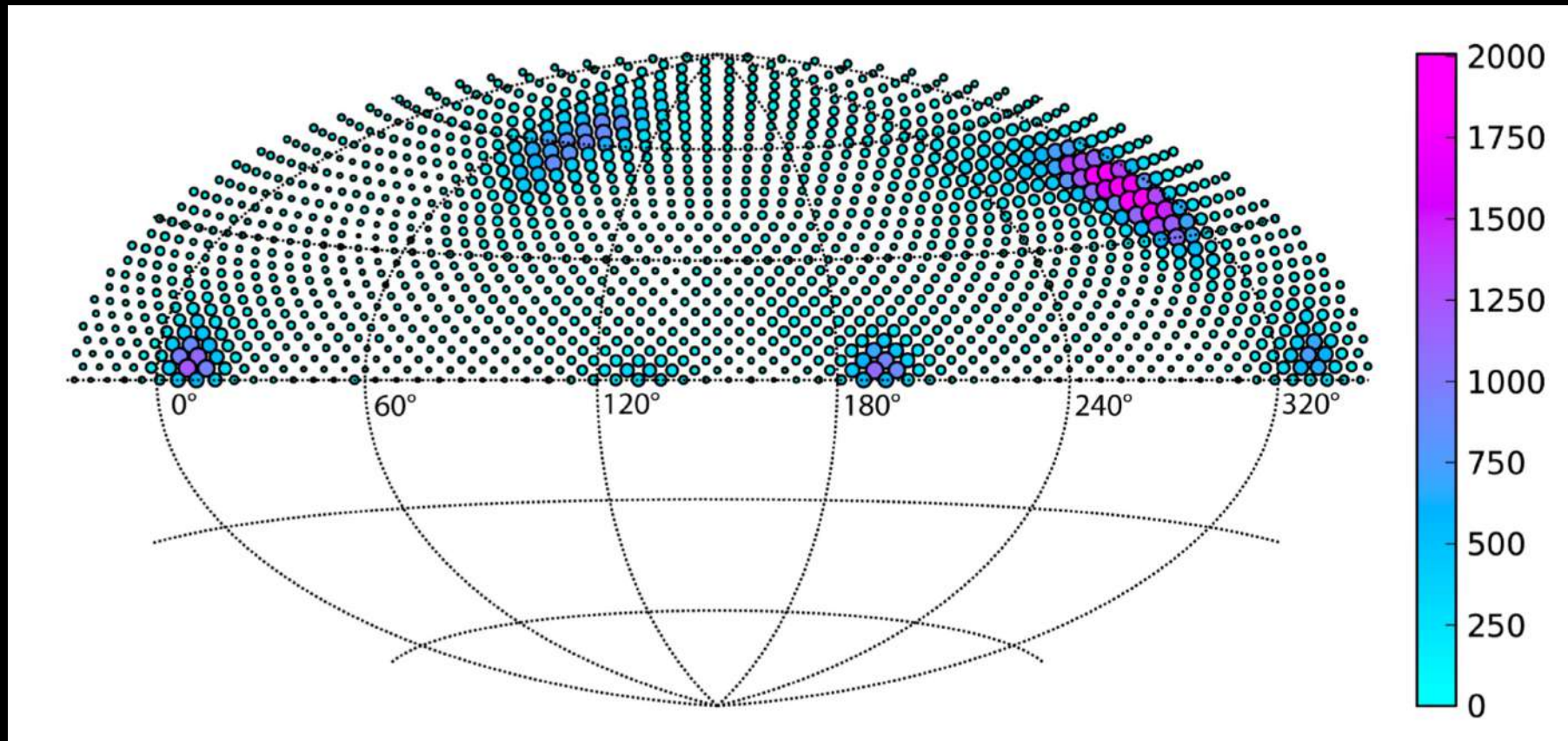
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Table 2 Angular sampling necessary to obtain a given resolution according to the Shannon theorem.

Resolution (Å)	Sampling (°)
50	8.1
30	4.9
20	3.3
15	2.5
12	2.0
10	1.6
8	1.3
6	1.0
5	0.82
4	0.65
3	0.49
2	0.33
1	0.16

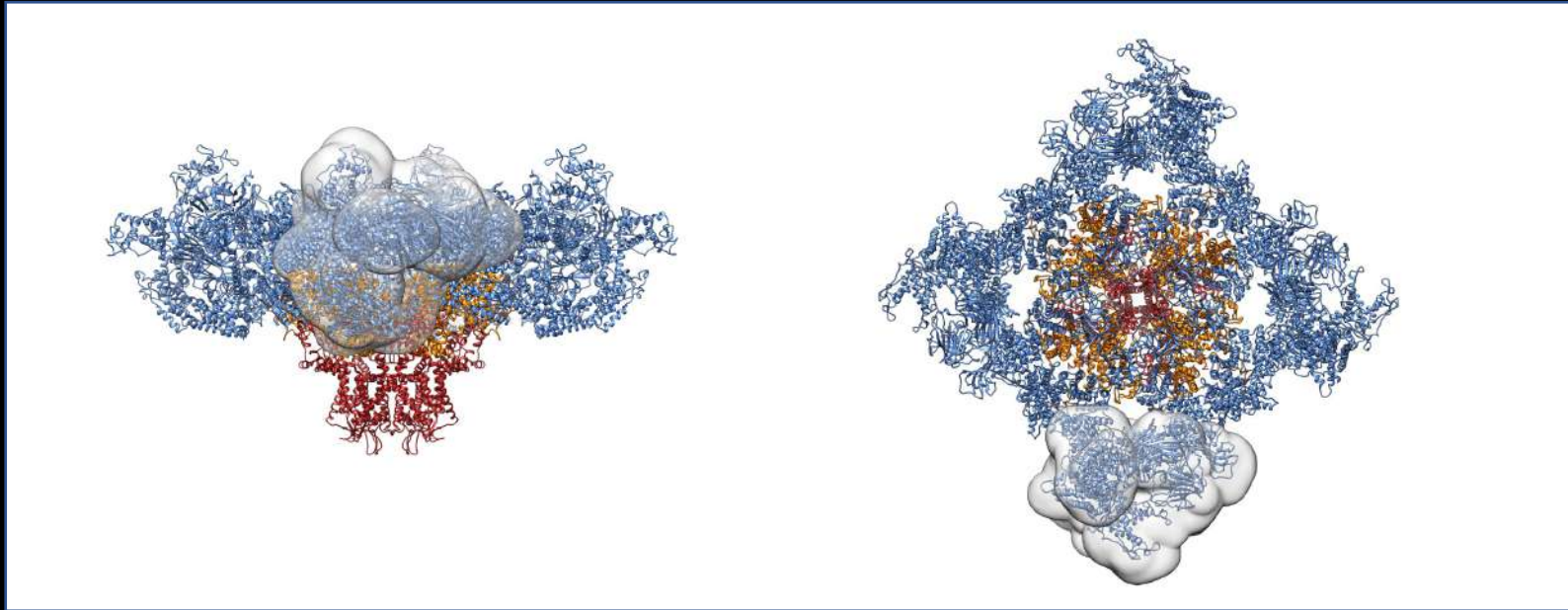
Aligning particles in 3D

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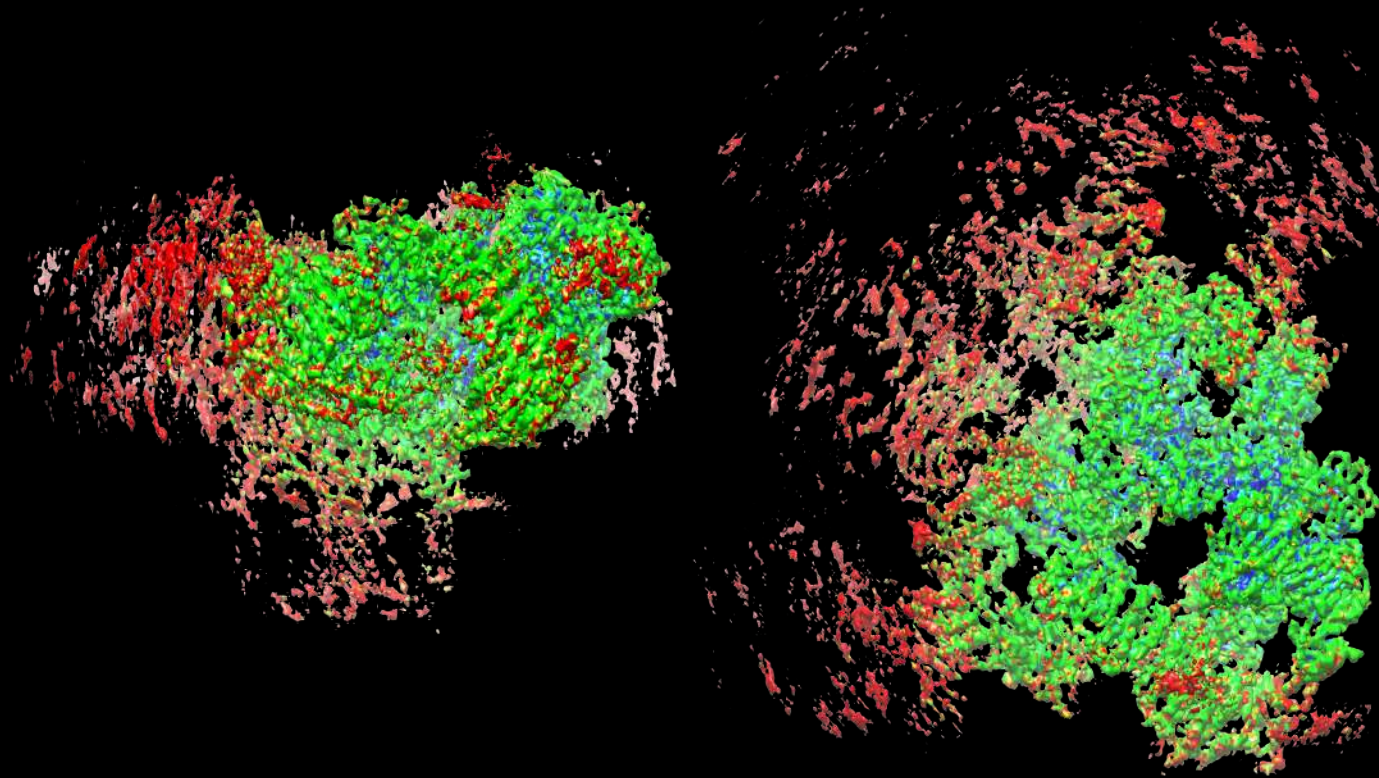
Aligning particles in 3D

- Local refinement



Aligning particles in 3D

- Local refinement





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